

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/719,346	CHEN, CHIA-TEH
	Examiner	Art Unit
	Emmanuel Sayoc	3746

SEARCHED			
Class	Subclass	Date	Examiner
417	423.15	11/5/05	ECS
	423.3		
	423.5		
416	5		
	99		
	100		
	110		
	123		
	130	11/7/05	ECS

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See Dif.	Search	11/7/05	(EZS)
Burst			